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BUK7613-100E

N-channel TrenchMOS standard level FET

5 October 2012

Product data sheet

1. Product profile

1.1 General description

Standard level N-channel MOSFET in a SOT404 package using TrenchMOS technology. This product has been designed and qualified to AEC Q101 standard for use in high performance automotive applications.

1.2 Features and benefits

- AEC Q101 compliant
- Repetitive avalanche rated
- Suitable for thermally demanding environments due to 175 °C rating
- True standard level gate with VGS(th) rating of greater than 1V at 175 °C

1.3 Applications

- 12V, 24V and 48V Automotive systems
- Motors, lamps and solenoid control
- Start-Stop micro-hybrid applications
- Transmission control
- Ultra high performance power switching

1.4 Quick reference data

Table 1. Quick reference data

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|--------------------------------|----------------------------------|--|-----|------|------|------------------|
| V_{DS} | drain-source voltage | $T_j \geq 25 \text{ }^\circ\text{C}; T_j \leq 175 \text{ }^\circ\text{C}$ | - | - | 100 | V |
| I_D | drain current | $V_{GS} = 10 \text{ V}; T_{mb} = 25 \text{ }^\circ\text{C}$; Fig. 1 | - | - | 72 | A |
| P_{tot} | total power dissipation | $T_{mb} = 25 \text{ }^\circ\text{C}$; Fig. 2 | - | - | 182 | W |
| Static characteristics | | | | | | |
| R_{DSon} | drain-source on-state resistance | $V_{GS} = 10 \text{ V}; I_D = 20 \text{ A}; T_j = 25 \text{ }^\circ\text{C}$; Fig. 11 | - | 10.2 | 13 | $\text{m}\Omega$ |
| Dynamic characteristics | | | | | | |
| Q_{GD} | gate-drain charge | $V_{GS} = 10 \text{ V}; I_D = 20 \text{ A}; V_{DS} = 80 \text{ V}$; $T_j = 25 \text{ }^\circ\text{C}$; Fig. 13 ; Fig. 14 | - | 25.4 | 35.6 | nC |



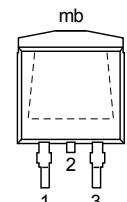
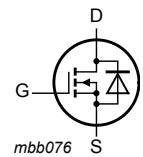
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2. Pinning information

Table 2. Pinning information

| Pin | Symbol | Description | Simplified outline | Graphic symbol |
|-----|--------|-----------------------------------|--|---|
| 1 | G | gate | | |
| 2 | D | drain | | |
| 3 | S | source | | |
| mb | D | mounting base; connected to drain |  D2PAK (SOT404) |  |

3. Ordering information

Table 3. Ordering information

| Type number | Package | | |
|--------------|---------|--|---------|
| | Name | Description | Version |
| BUK7613-100E | D2PAK | plastic single-ended surface-mounted package (D2PAK); 3 leads (one lead cropped) | SOT404 |

4. Marking

Table 4. Marking codes

| Type number | Marking code |
|--------------|--------------|
| BUK7613-100E | BUK7613-100E |

5. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol | Parameter | Conditions | Min | Max | Unit |
|-----------|-------------------------|---|-----|-----|------|
| V_{DS} | drain-source voltage | $T_j \geq 25^\circ\text{C}$; $T_j \leq 175^\circ\text{C}$ | - | 100 | V |
| V_{DGR} | drain-gate voltage | $R_{GS} = 20\text{ k}\Omega$ | - | 100 | V |
| V_{GS} | gate-source voltage | $T_j \leq 175^\circ\text{C}$; DC | -20 | 20 | V |
| I_D | drain current | $T_{mb} = 25^\circ\text{C}$; $V_{GS} = 10\text{ V}$; Fig. 1 | - | 72 | A |
| | | $T_{mb} = 100^\circ\text{C}$; $V_{GS} = 10\text{ V}$; Fig. 1 | - | 51 | A |
| I_{DM} | peak drain current | $T_{mb} = 25^\circ\text{C}$; pulsed; $t_p \leq 10\text{ }\mu\text{s}$; Fig. 4 | - | 288 | A |
| P_{tot} | total power dissipation | $T_{mb} = 25^\circ\text{C}$; Fig. 2 | - | 182 | W |
| T_{stg} | storage temperature | | -55 | 175 | °C |
| T_j | junction temperature | | -55 | 175 | °C |

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| Symbol | Parameter | Conditions | | Min | Max | Unit |
|-----------------------------|--|---|--------|-----|-----|------|
| Source-drain diode | | | | | | |
| I_S | source current | $T_{mb} = 25^\circ C$ | | - | 72 | A |
| I_{SM} | peak source current | pulsed; $t_p \leq 10 \mu s$; $T_{mb} = 25^\circ C$ | | - | 288 | A |
| Avalanche ruggedness | | | | | | |
| $E_{DS(AL)S}$ | non-repetitive drain-source avalanche energy | $I_D = 72 A$; $V_{sup} \leq 100 V$; $R_{GS} = 50 \Omega$; $V_{GS} = 10 V$; $T_{j(init)} = 25^\circ C$; unclamped; Fig. 3 | [1][2] | - | 121 | mJ |

[1] Single-pulse avalanche rating limited by maximum junction temperature of 175 °C.

[2] Refer to application note AN10273 for further information.

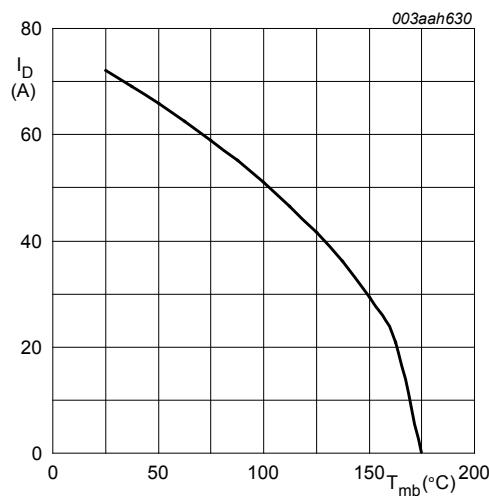


Fig. 1. Continuous drain current as a function of mounting base temperature

$V_{GS} \geq 10 V$

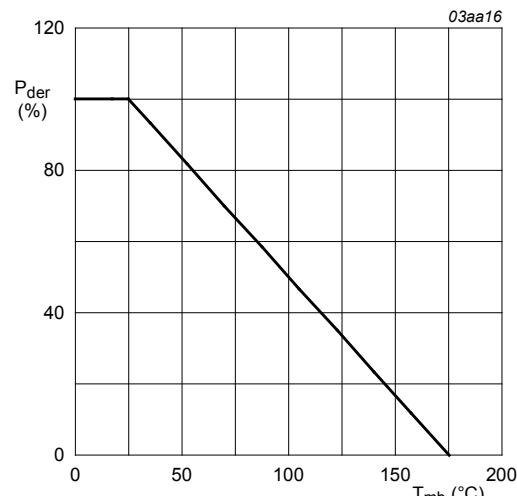


Fig. 2. Normalized total power dissipation as a function of mounting base temperature

$$P_{der} = \frac{P_{tot}}{P_{tot}(25^\circ C)} \times 100 \%$$

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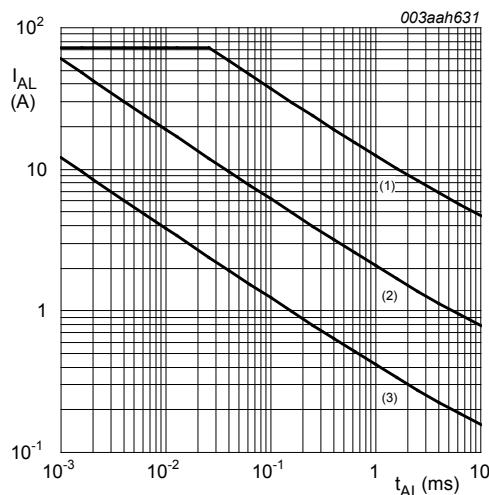


Fig. 3. Avalanche rating; avalanche current as a function of avalanche time

(1) $T_j \text{ (init)} = 25^\circ\text{C}$; (2) $T_j \text{ (init)} = 150^\circ\text{C}$; (3) Repetitive Avalanche

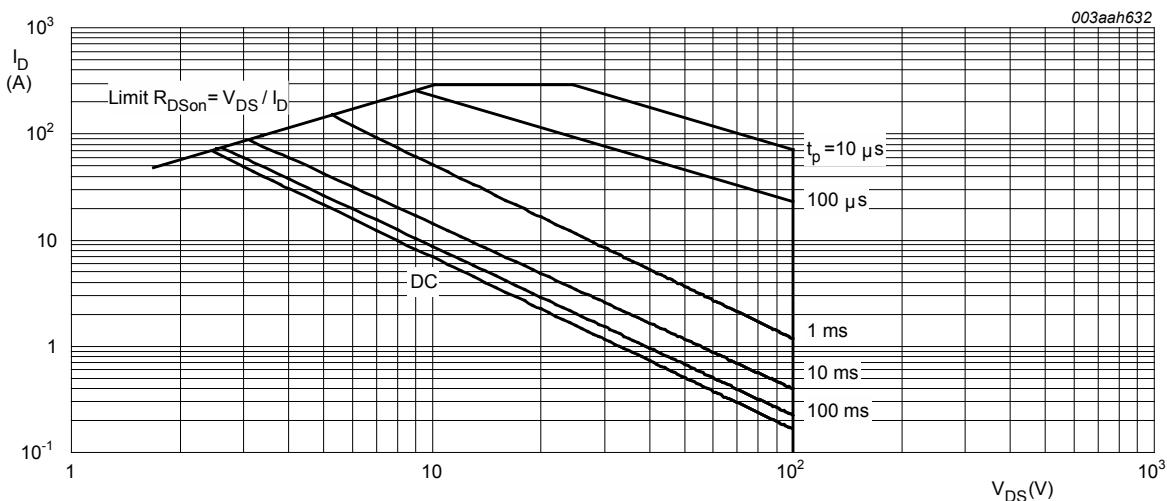


Fig. 4. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

$T_{mb} = 25^\circ\text{C}$; I_{DM} is a single pulse

6. Thermal characteristics

Table 6. Thermal characteristics

| Symbol | Parameter | Conditions | | Min | Typ | Max | Unit |
|----------------|---|--|--|-----|-----|------|------|
| $R_{th(j-mb)}$ | thermal resistance from junction to mounting base | Fig. 5 | | - | - | 0.82 | K/W |
| $R_{th(j-a)}$ | thermal resistance from junction to ambient | minimum footprint ; mounted on a printed-circuit board | | - | 50 | - | K/W |

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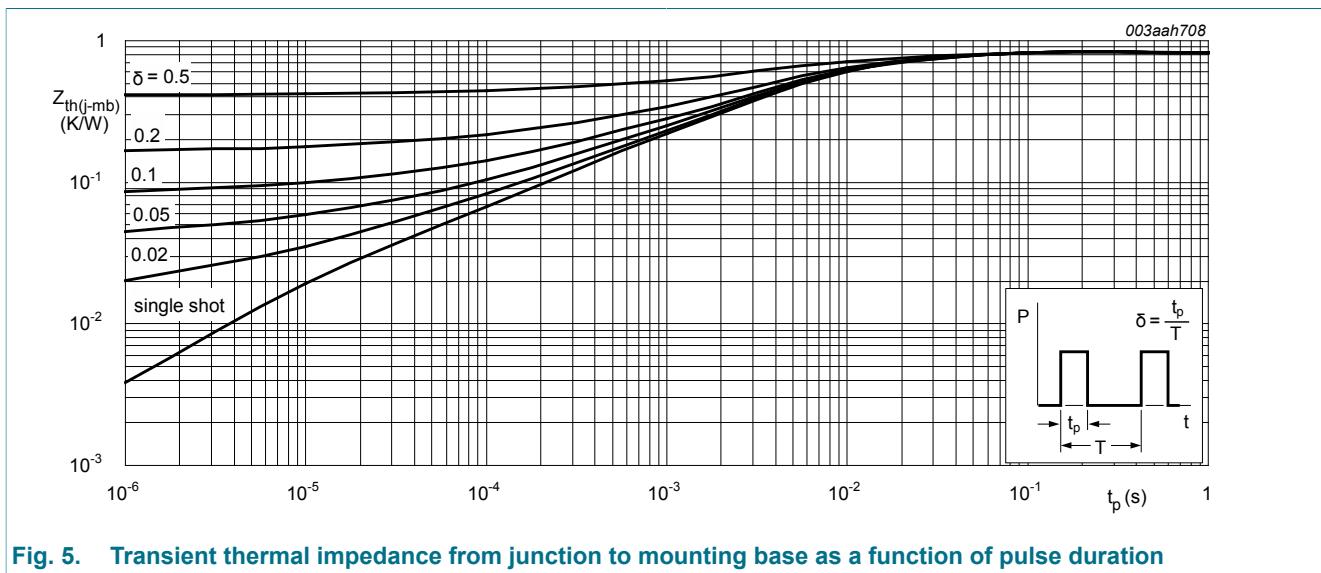


Fig. 5. Transient thermal impedance from junction to mounting base as a function of pulse duration

7. Characteristics

Table 7. Characteristics

| Symbol | Parameter | Conditions | | Min | Typ | Max | Unit |
|--------------------------------|----------------------------------|---|--|------|------|------|------------|
| Static characteristics | | | | | | | |
| V _{(BR)DSS} | drain-source breakdown voltage | I _D = 250 μ A; V _{GS} = 0 V; T _j = 25 °C | | 100 | - | - | V |
| | | I _D = 250 μ A; V _{GS} = 0 V; T _j = -55 °C | | 90 | - | - | V |
| Dynamic characteristics | | | | | | | |
| V _{GS(th)} | gate-source threshold voltage | I _D = 1 mA; V _{DS} = V _{GS} ; T _j = 25 °C; Fig. 9 ; Fig. 10 | | 2.4 | 3 | 4 | V |
| | | I _D = 1 mA; V _{DS} = V _{GS} ; T _j = 175 °C; Fig. 9 | | 1 | - | - | V |
| I _{DSS} | drain leakage current | I _D = 1 mA; V _{DS} = V _{GS} ; T _j = -55 °C; Fig. 9 | | - | - | 4.5 | V |
| | | V _{DS} = 100 V; V _{GS} = 0 V; T _j = 25 °C | | - | 0.06 | 1 | μ A |
| I _{GSS} | gate leakage current | V _{DS} = 100 V; V _{GS} = 0 V; T _j = 175 °C | | - | - | 500 | μ A |
| | | V _{GS} = 20 V; V _{DS} = 0 V; T _j = 25 °C | | - | 2 | 100 | nA |
| R _{DSon} | drain-source on-state resistance | V _{GS} = -20 V; V _{DS} = 0 V; T _j = 25 °C | | - | 2 | 100 | nA |
| | | V _{GS} = 10 V; I _D = 20 A; T _j = 25 °C; Fig. 11 | | - | 10.2 | 13 | m Ω |
| R _G | gate resistance | V _{GS} = 10 V; I _D = 20 A; T _j = 175 °C; Fig. 11 ; Fig. 12 | | - | - | 35.1 | m Ω |
| | | f = 1 MHz | | 0.48 | 0.96 | 1.92 | Ω |
| Dynamic characteristics | | | | | | | |
| Q _{G(tot)} | total gate charge | I _D = 20 A; V _{DS} = 80 V; V _{GS} = 10 V; T _j = 25 °C; Fig. 13 ; Fig. 14 | | - | 69.4 | 97.2 | nC |
| Q _{GS} | gate-source charge | | | - | 15.5 | 21.7 | nC |

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| Symbol | Parameter | Conditions | | Min | Typ | Max | Unit |
|---------------------------|------------------------------|---|--|-----|------|-------|------|
| Q_{GD} | gate-drain charge | | | - | 25.4 | 35.6 | nC |
| C_{iss} | input capacitance | $V_{GS} = 0 \text{ V}$; $V_{DS} = 20 \text{ V}$; $f = 1 \text{ MHz}$; $T_j = 25 \text{ }^\circ\text{C}$; Fig. 15 | | - | 3400 | 4533 | pF |
| C_{oss} | output capacitance | $V_{GS} = 0 \text{ V}$; $V_{DS} = 25 \text{ V}$; $f = 1 \text{ MHz}$; $T_j = 25 \text{ }^\circ\text{C}$; Fig. 15 | | - | 327 | 392 | pF |
| C_{rss} | reverse transfer capacitance | | | - | 225 | 308 | pF |
| $t_{d(on)}$ | turn-on delay time | $V_{DS} = 80 \text{ V}$; $R_L = 4 \Omega$; $V_{GS} = 10 \text{ V}$; $R_{G(ext)} = 5 \Omega$ | | - | 17.5 | 26.3 | ns |
| t_r | rise time | | | - | 34 | 51 | ns |
| $t_{d(off)}$ | turn-off delay time | | | - | 44.8 | 67.2 | ns |
| t_f | fall time | | | - | 34.1 | 51.2 | ns |
| L_D | internal drain inductance | from upper edge of mounting base to centre of die | | - | 2.5 | - | nH |
| L_S | internal source inductance | measured from source lead to source bond pad; $T_j = 25 \text{ }^\circ\text{C}$ | | - | 7.5 | - | nH |
| Source-drain diode | | | | | | | |
| V_{SD} | source-drain voltage | $I_S = 20 \text{ A}$; $V_{GS} = 0 \text{ V}$; $T_j = 25 \text{ }^\circ\text{C}$; Fig. 16 | | - | 0.83 | 1.2 | V |
| t_{rr} | reverse recovery time | $I_S = 20 \text{ A}$; $dI_S/dt = -100 \text{ A}/\mu\text{s}$; $V_{GS} = 0 \text{ V}$; | | - | 48.8 | 63.4 | ns |
| Q_r | recovered charge | $V_{DS} = 25 \text{ V}$ | | - | 106 | 137.8 | nC |

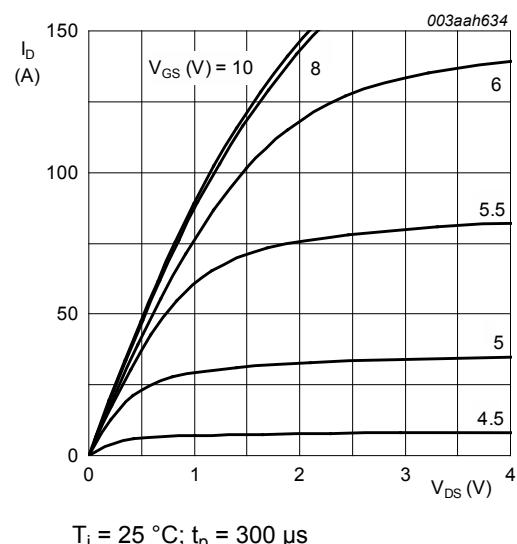


Fig. 6. Output characteristics; drain current as a function of drain-source voltage; typical values

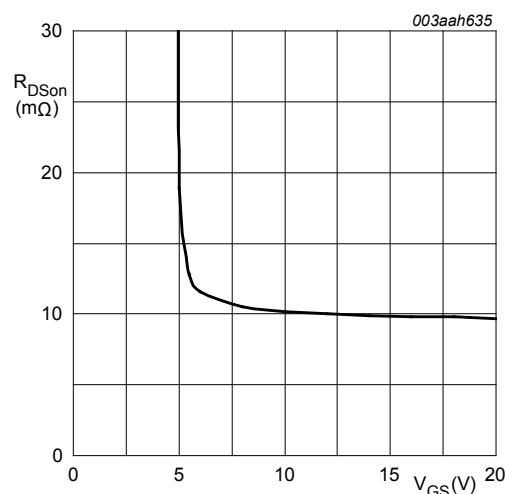


Fig. 7. Drain-source on-state resistance as a function of gate-source voltage; typical values

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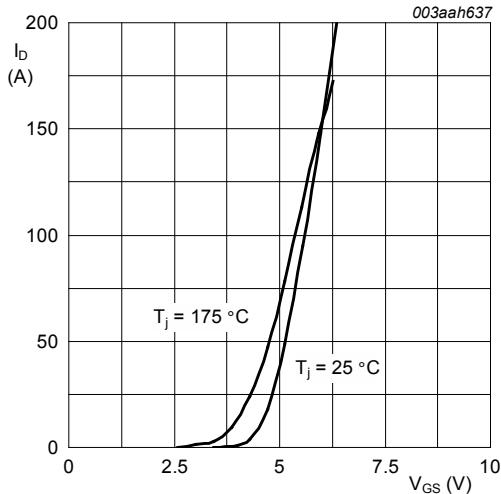


Fig. 8. Transfer characteristics; drain current as a function of gate-source voltage; typical values

$V_{DS} = 10V$

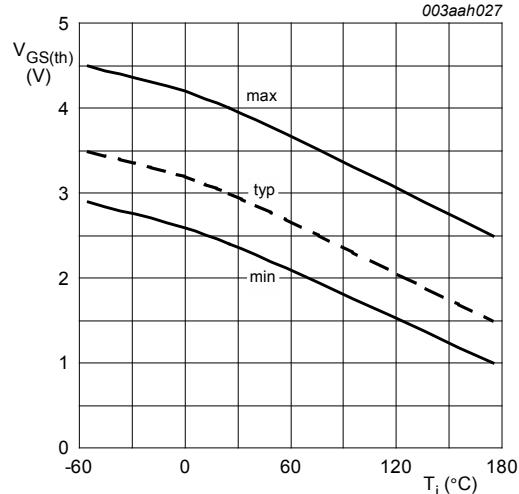


Fig. 9. Gate-source threshold voltage as a function of junction temperature

$I_D = 1\text{ mA}; V_{DS} = V_{GS}$

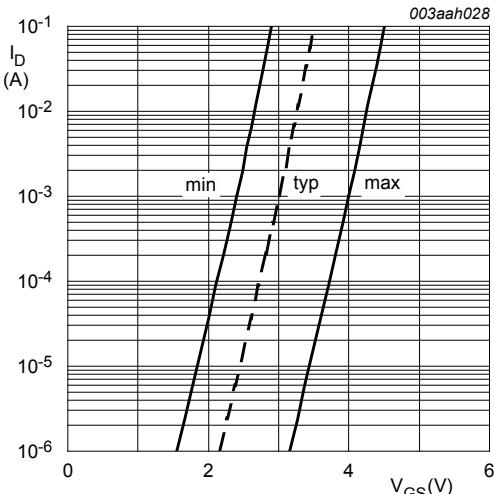
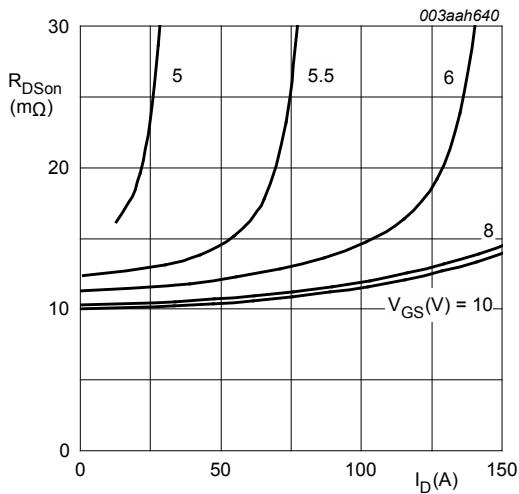


Fig. 10. Sub-threshold drain current as a function of gate-source voltage

$T_j = 25\text{ }^{\circ}\text{C}; V_{DS} = 5V$



$T_j = 25\text{ }^{\circ}\text{C}; t_p = 300\text{ }\mu\text{s}$

Fig. 11. Drain-source on-state resistance as a function of drain current; typical values

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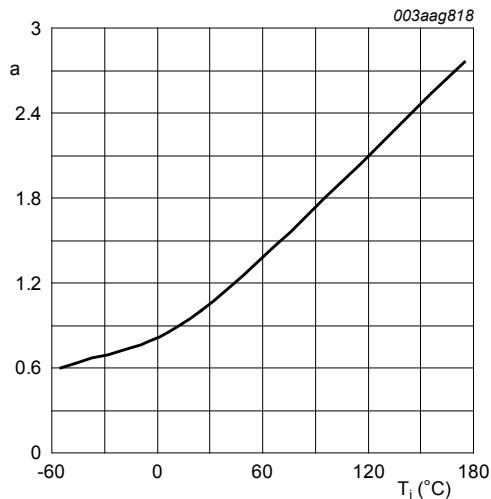


Fig. 12. Normalized drain-source on-state resistance factor as a function of junction temperature

$$a = \frac{R_{DSon}}{R_{DSon}(25\text{ }^{\circ}\text{C})}$$

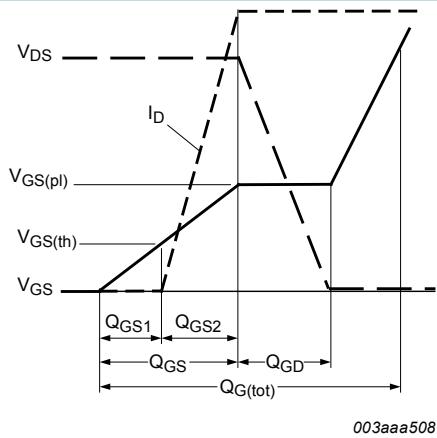


Fig. 14. Gate charge waveform definitions

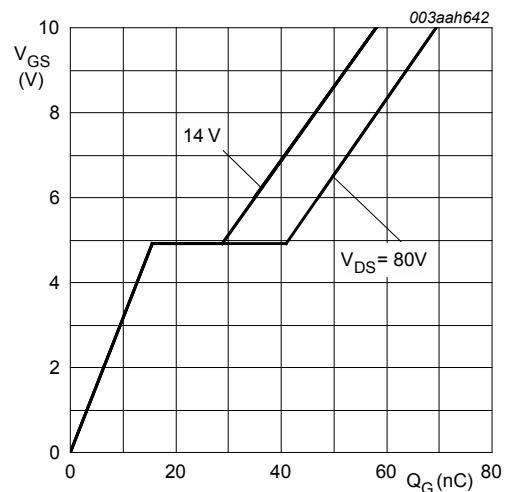


Fig. 13. Gate-source voltage as a function of gate charge; typical values

$T_j = 25\text{ }^{\circ}\text{C}; I_D = 20\text{ A}$

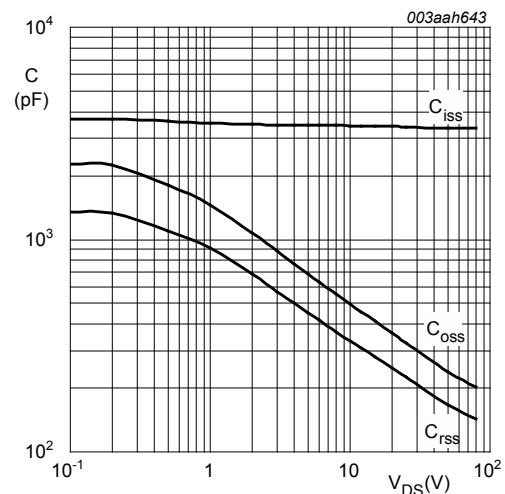
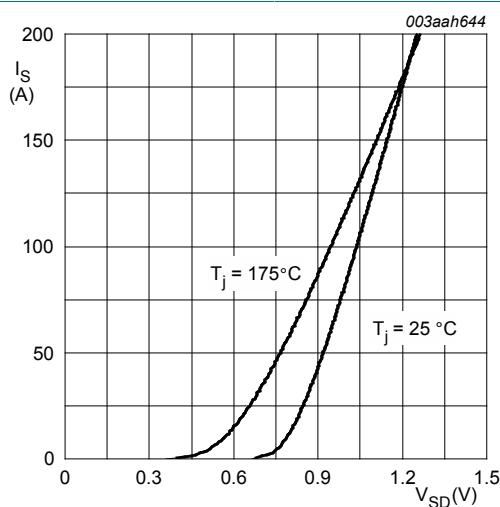


Fig. 15. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

$V_{GS} = 0\text{ V}; f = 1\text{ MHz}$

NXP Semiconductors**BUK7613-100E****N-channel TrenchMOS standard level FET****Fig. 16. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values** $V_{GS} = 0V$

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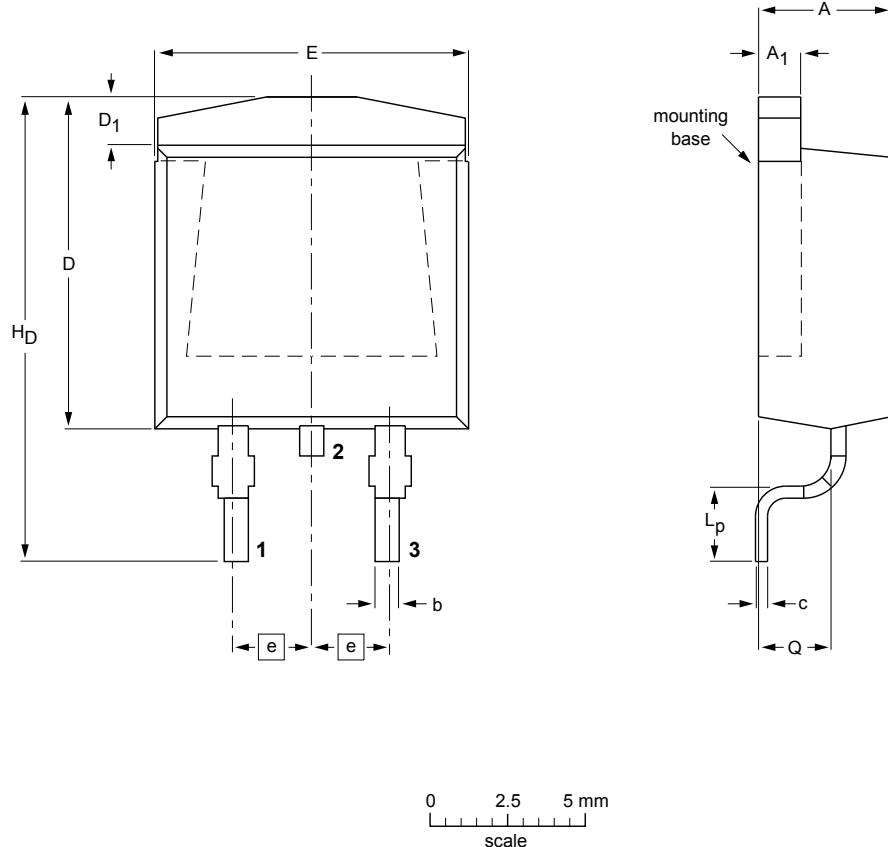
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8. Package outline

Plastic single-ended surface-mounted package (D2PAK); 3 leads (one lead cropped)

SOT404



DIMENSIONS (mm are the original dimensions)

| UNIT | A | A_1 | b | c | $D_{max.}$ | D_1 | E | e | L_p | H_D | Q |
|------|--------------|--------------|--------------|--------------|------------|--------------|---------------|------|--------------|----------------|--------------|
| mm | 4.50 4.10 | 1.40 1.27 | 0.85 0.60 | 0.64 0.46 | 11 | 1.60 1.20 | 10.30 9.70 | 2.54 | 2.90 2.10 | 15.80 14.80 | 2.60 2.20 |

| OUTLINE VERSION | REFERENCES | | | | EUROPEAN PROJECTION | ISSUE DATE |
|-----------------|------------|-------|-------|--|---------------------|----------------------|
| | IEC | JEDEC | JEITA | | | |
| SOT404 | | | | | | 05-02-11 06-03-16 |

Fig. 17. Package outline D2PAK (SOT404)

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9. Legal information

9.1 Data sheet status

| Document status [1][2] | Product status [3] | Definition |
|--------------------------------|--------------------|---|
| Objective [short] data sheet | Development | This document contains data from the objective specification for product development. |
| Preliminary [short] data sheet | Qualification | This document contains data from the preliminary specification. |
| Product [short] data sheet | Production | This document contains the product specification. |

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
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